

Notice of References Cited	Application/Control No. 10/711,168	Applicant(s)/Patent Under Reexamination BREILAND ET AL.	
	Examiner Russell Frejd	Art Unit 2128	Page 1 of 1

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*	B	US-6,584,596	06-2003	Buffet et al.	716/1
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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